NSN 6625-00-222-1117

Semiconductor Device Test Set - Page 1 of 1



View Online at https://aerobasegroup.com/nsn/6625-00-222-1117 Width: 4.250 inches Length: 5.500 inches Joint Electronics Type Designation System Item Name: Test set, semiconductor device Joint Electronics Type Designation System Item Type Number: Ts-3253/tpm-39 **Material And Location:** Aluminum housing Inclosure Feature: Single item w/housing **Test Type For Which Designed:** Microwave diode current **Operating Test Capability:** Microamphere meter range 0-1000 ua dc Height: 3.880 inches **Surface Treatment:** Enamel **Surface Treatment:** Enamel **Fsc Application Data:** Test set, elect. Equip. Shelf Life: N/a **Unit Of Measure:** Demilitarization: No Fiig: T228-a